Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/028,344	BEYER ET AL.
Examiner	Art Unit
AJIT G. PATEL	2664

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Class	Subclass	Date	Examiner
370	389 391	3/1/26	m
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375	354 371		
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INT	INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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